- Designed Specifically for High-Speed Memory Decoders and Data Transmission Systems
- Incorporate Two Enable Inputs to Simplify Cascading and/or Data Reception
- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

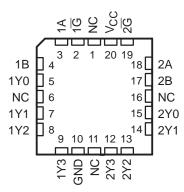
The 'ALS139 are dual 2-line to 4-line decoders/demultiplexers designed for use in high-performance memory-decoding or data-routing applications requiring very short propagation delay times. In high-performance memory systems, these devices can minimize the effects of system decoding. When employed with high-speed memories utilizing a fast-enable circuit, the delay times of these decoders and the enable time of the memory are usually less than the typical access time of the memory. Therefore, the effective system decoder is negligible.

The 'ALS139 comprise two individual 2-line to 4-line decoders in a single package. The active-low enable (\overline{G}) input can be used as a data line in demultiplexing applications. These

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SN54ALS139 J PACKAGE SN74ALS139 D OR N PACKAGE (TOP VIEW)								
1 G 1 A 1 B 1 Y0 1 Y1 1 Y2 1 Y3 GND	2 3 4 5 6	16 15 14 13 12 11 10 9	V _{CC} 2G 2A 2B 2Y0 2Y1 2Y2 2Y3					

SN54ALS139 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

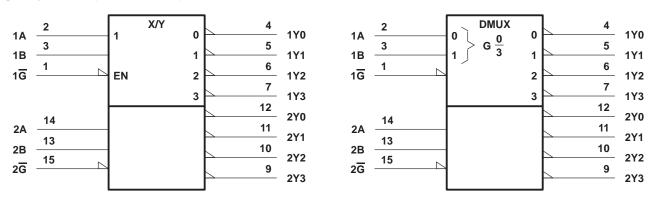
decoders/demultiplexers feature fully buffered inputs, each of which represents only one normalized load to its driving circuit. All inputs are clamped with high-performance Schottky diodes to suppress line ringing and simplify system design.

The SN54ALS139 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74ALS139 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE									
INPUTS			OUTPUTS						
ENABLE	-		0012015						
G			Y0	Y1	Y2	Y3			
Н	Х	Х	Н	Н	Н	Н			
L	L	L	L	Н	Н	н			
L	L	н	н	L	Н	н			
L	Н	L	н	Н	L	н			
L	Н	Н	н	Н	Н	L			

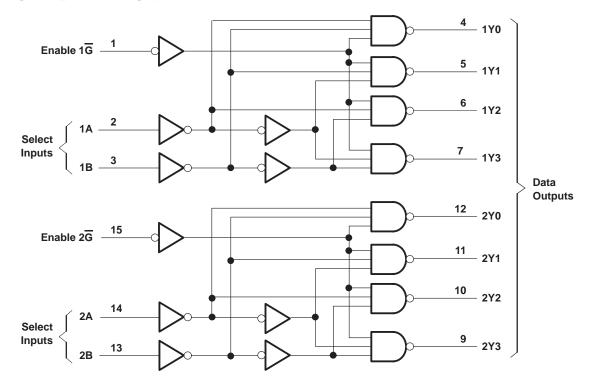
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logic symbols (alternatives)[†]



[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, and N packages.

logic diagram (positive logic)



Pin numbers shown are for the D, J, and N packages.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{CC} Input voltage, V _I	
Operating free-air temperature range, T _A : SN54ALS139	–55°C to 125°C
SN74ALS139	0°C to 70°C
Storage temperature range	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54ALS139		SN74ALS139			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.7			0.8	V
ЮН	High-level output current			-0.4			-0.4	mA
IOL	Low-level output current			4			8	mA
TA	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54ALS139			SN74ALS139			UNIT
PARAMETER			MIN	TYP‡	MAX	MIN	typ‡	MAX	UNIT
VIK	$V_{CC} = 4.5 V,$	II = -18 mA			-1.2			-1.2	V
VOH	V_{CC} = 4.5 V to 5.5 V,	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2	2		V _{CC} -2	2		V
Vol		$I_{OL} = 4 \text{ mA}$		0.25	0.4		0.25	0.4	v
VOL	$V_{CC} = 4.5 V$	I _{OL} = 8 mA					0.35	0.5	
lj	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
Чн	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ
Ι _{ΙL}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.1			-0.1	mA
۱ ₀ §	V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
ICC	V _{CC} = 5.5 V			8	13		8	13	mA

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

§ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

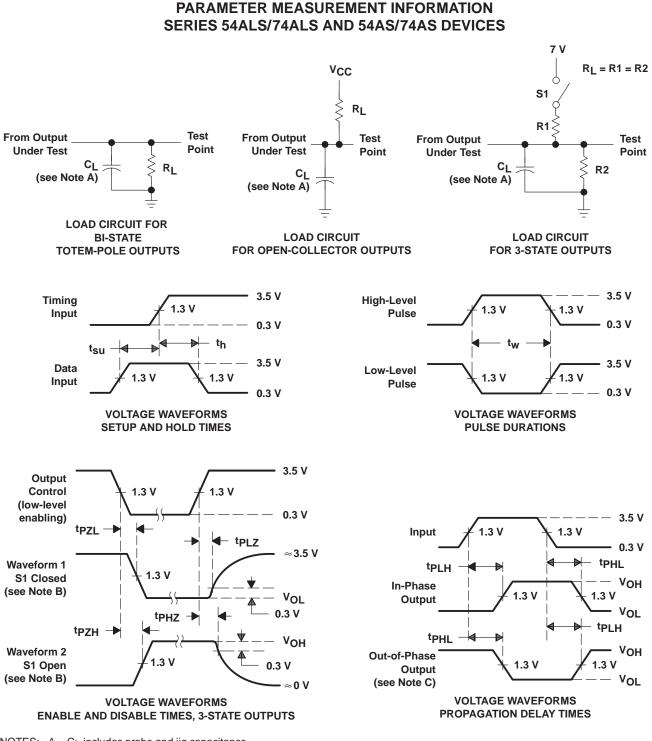
switching characteristics (see Figure 1)

PARAMETER	FROM TO (INPUT) (OUTPUT)		AMETER			V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R _L = 500 Ω, T _A = MIN to MAX¶			
			SN54ALS139		SN74ALS139				
			MIN	MAX	MIN	MAX			
^t PLH	A or B	Y	3	17	3	14			
^t PHL			3	17	3	14	ns		
^t PLH	G	Y	3	17	3	14			
^t PHL	6		3 18	3	15	ns			

 \P For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, t_r = t_f = 2 ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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